

RELIABILITY DATA					
PMU9053 in LTM4649, LTM4648					
9/9/2019					
• J-STD-020 MSL 3 PRECONDITIONING: 192h +30°C/60%R.H. SOAK, 3x REFLOW AT +245°C PEAK					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE		NUMBER OF FAILURES
LTM4649	261 261	1912	1912		0 0
• EXTENDED PRECONDITIONING: 216h +30°C/60%R.H. SOAK, 3x REFLOW AT +245°C PEAK					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE		NUMBER OF FAILURES
LTM4649	50 50	1912	1813		0 0
• HIGH TEMPERATURE STORAGE +150°C					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS AT	NUMBER OF FAILURES
LTM4649	77 77	1912	1912	77.00 77.00	0 0
• TEMP CYCLE FROM -55°C to +125°C ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
LTM4649	77 77	1912	1912	38.50 38.50	0 0
• THERMAL SHOCK FROM -55°C to +125°C ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
LTM4649	77 77	1912	1912	38.50 38.50	0 0
• UNBIASED HIGHLY ACCELERATED STRESS TEST +130°C/85% R.H. ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS AT +130°C	NUMBER OF FAILURES
LTM4649	77 77	1912	1912	7.38 7.38	0 0
(1) Environmental stress are preceded by J-STD-020 Level 3 Preconditioning					